



# Microscope

Name	Photo	Description	Link
JEOL JCM-6000 NeoScope Versatile Benchtop SEM	 A white, compact benchtop scanning electron microscope (SEM) with a grey top cover. The front panel features the JEOL logo, a control panel with a blue and green indicator light, and two silver knobs. The device is supported by four black feet.	<p>Specification Highlight: Imaging mode: Secondary electron image and Backscattered electron image</p> <p>Magnification:</p> <p>10x to 60,000x ( Secondary electron image) 10x to 30,000x (Backscattered electron image)</p> <p>Accelerating voltage:</p> <p>5kV, 10kV, 15kV (Secondary electron image) 10kV, 15kV (Backscattered electron image)</p> <p>Maximum sample size: 70mm diameter with 50 mm height</p> <p>Sample material: conductive materials and non-conductive materials</p> <p>Vacuum modes: High and Low</p> <p>Optional functions: Element analysis device(EDS), tilt and rotation</p> <p>File format export: BMP, TIFF, JPEG</p>	<a href="#">Detailed information</a>

Name	Photo	Description	Link
CRAIC 308 PV UV-Visible-NIR microscope Spectrophotometer	 A photograph of a CRAIC 308 PV UV-Visible-NIR microscope Spectrophotometer. The instrument is primarily white with blue accents at the base. It features a large red octagonal sign on top with the word 'CRAIC' in blue. The main body includes a control panel with several buttons and a display, a stage with a sample holder, and a lens assembly. The base has a blue and white striped pattern.		<a href="#">Detailed information</a>